Deposition	method	TOI	compound	semiconductor	Comming
device					

Deposition o	entimos roteubrostines brucquios rot borten					
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Abstract						
A deposition method of a compound semiconductor forming a semiconductor device comprises the steps of; covering the surface of a compound semiconductor containing a V group element with a III group element with a thickness of one or more monolayers; and forming a second compound semiconductor containing a V group element different from said V group element on said III group element while utilizing said III group element as a protective film for preventing the desorption of said V group element.						